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built-in voltage of a PN junction, since the diodes are connected to each other in a forward direction. As is well known in the art the built-in voltage of the PN junction may vary.

[0028] Yet, as the present diodes are connected in series, a voltage of the node A is dropped down by an amount (number of diodes  $D_n \times 0.7V$ ) so as to be applied to the substrate. For instance, if 5 diodes are connected in series to each other, a voltage at a node B becomes the voltage attained by subtracting 3.5V from the voltage at node A. Once the voltage over 3.5V is applied to the pad, all the diodes are turned on so as to increase a potential of the substrate. If the potential of the substrate becomes high, a voltage drop (for example, 0.7V) occurs with ease between the source of the bipolar transistor B1 and substrate. Thus, the triggering voltage of the bipolar transistor B1 is reduced.

[0029] As a result, a triggering of the bipolar transistor B1 may occur even at a low voltage. If the bipolar transistor B1 is turned on at the low voltage, a voltage applied to the NMOS transistor N1 and its gate insulating layer is reduced. Thus, the influence or damage to the gate insulating layer of the NMOS transistor N1 is decreased.

[0030] Moreover, when measured by applying a voltage to the substrate of the NMOS transistor N1 in the manner of the present invention, a second breakdown current ( $I_{t2}$  value) representing ESD performance becomes even higher.

[0031] As mentioned in the above description, the present invention improves ESD performance by turning on the parasitic bipolar transistor of the NMOS transistor at a voltage lower than that of the conventional art.

[0032] Accordingly, the present invention allows the prevention of a gate insulating layer from receiving a high voltage by turning on a protection circuit at a lower

voltage so as to shunt the ESD current as well as improve ESD performance by increasing a magnitude of  $I_{t2}$ .

[0033] The invention being thus described, it will be obvious that the same may be varied in many ways. Such variations are not to be regarded as a departure from the spirit and scope of the invention, and all such modifications as would be obvious to one skilled in the art are intended to be included within the scope of the following claims.

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